

IBM DOCKET: FIS920000191US1

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

INVENTOR: Christopher P. Ausschnitt) EXAMINER:
SERIAL NO.:) ART UNIT:
FILING DATE:) DATE: November 30, 2000
FOR: FOCUS CONTROL SYSTEM)

Jc974 U.S. PTO
09/765148
01/17/01

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In accordance with 37 CFR 1.56, 1.97 and 1.98, the following items are made of record to assist the Patent & Trademark Office in its examination of this application and is, in the opinion of the attorney designated below for applicant(s), information relevant to the closest prior art of which that person is aware. The filing of this Information Disclosure Statement shall not be construed as a representation that a search has been made or that no other art than that identified exists.

PATENT NO.

5,629,772
5,712,707
5,731,877
5,756,242
5,757,507
5,776,645
5,805,290
5,914,784
5,928,822
5,949,547

INVENTOR

Ausschnitt
Ausschnitt et al.
Ausschnitt
Koizumi et al.
Ausschnitt et al.
Barr et al.
Ausschnitt et al.
Ausschnitt et al.
Rhyu
Tseng et al.

ISSUE DATE

May 13, 1997
January 27, 1998
March 24, 1998
May 26, 1998
May 26, 1998
July 7, 1998
September 8, 1998
June 22, 1999
July 27, 1999
September 7, 1999

5,953,128	Ausschnitt et al.	September 14, 1999
5,965,309	Ausschnitt et al.	October 12, 1999
5,968,693	Adams	October 19, 1999
5,976,740	Ausschnitt et al.	November 2, 1999
5,981,119	Adams	November 9, 1999
5,985,495	Okumura et al.	November 16, 1999
6,004,706	Ausschnitt et al.	December 21, 1999
6,027,842	Ausschnitt et al.	February 22, 2000
6,128,089	Ausschnitt et al.	October 3, 2000
6,130,750	Ausschnitt et al.	October 10, 2000
6,137,578	Ausschnitt	October 24, 2000

OTHER PUBLICATIONS

Intellectual Property Network, *Method for Measuring Semiconductor Lithographic Tool Focus and Exposure*, IBM Technical Disclosure Bulletin, July 1987, pages 516-518.

Alexander Starikov, *Exposure Monitor Structure* SPIE Integrated Circuit Metrology, Inspection, and Process Control IV, Vol 1261, 1990, pages 315-324

A copy of each of the foregoing items and Form PTO 1449 are enclosed herewith.

Respectfully submitted,

By:



Attorney: **Peter W. Peterson**

Reg. No.: **31,867**

DeLIO & PETERSON, LLC
121 Whitney Avenue
New Haven, CT 06510
(203) 787-0595

CERTIFICATE OF MAILING UNDER 37 CFR 1.10

I hereby certify that, on the date shown below, this correspondence is being deposited with the United States Postal Service in an envelope addressed to the Assistant Commissioner for Patents, Washington, D.C. 20231, as "Express Mail Post Office to Addressee"

Mailing Label No. EK140407634US on 1-17-01

Name of person mailing paper Karen Cing-Mars Signature [Signature] Date: 1-17-01